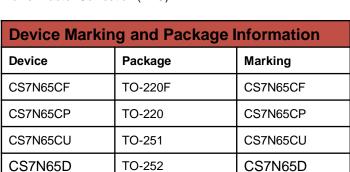
## **650V N-Channel MOSFET**

#### **FEATURES**

- Fast switching
- 100% avalanche tested
- Improved dv/dt capability

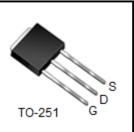
#### **APPLICATIONS**

- Switch Mode Power Supply (SMPS)
- Uninterruptible Power Supply (UPS)
- Power Factor Correction (PFC)

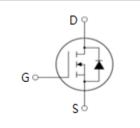












<b>Absolute Maximum Ratings</b> $T_C = 25^{\circ}C$ , unless otherwise noted							
Parameter	Cumbal		Unit				
raidinetei	Symbol	TO-220F	TO-220	TO-251	TO-252	Onit	
Drain-Source Voltage (V <sub>GS</sub> = 0V)	V <sub>DSS</sub>	650			٧		
Continuous Drain Current	I <sub>D</sub>	7			Α		
Pulsed Drain Current (note1)	I <sub>DM</sub>	28			Α		
Gate-Source Voltage	V <sub>GSS</sub>	±30			V		
Single Pulse Avalanche Energy (note2)	E <sub>AS</sub>	165			mJ		
Avalanche Current (note1)	I <sub>AS</sub>	5.76			А		
Repetitive Avalanche Energy (note1)	E <sub>AR</sub>	100			mJ		
Power Dissipation (T <sub>C</sub> = 25°C)	P <sub>D</sub>	63		97	_	W	
Operating Junction and Storage Temperature Range	T <sub>J</sub> , T <sub>stg</sub>	-55~+150		°C			

Thermal Resistance						
Parameter	Symbol		11:4			
		TO-220F	TO-220	TO-251	TO-252	Unit
Thermal Resistance, Junction-to-Case	R <sub>thJC</sub>	1.98	1.29		K/W	
Thermal Resistance, Junction-to-Ambient	R <sub>thJA</sub>	62.5		60		rv VV



Parameter			Value			
	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static						
Drain-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS} = 0V, I_D = 250\mu A$	650			V
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{DS} = 650V, V_{GS} = 0V, T_{J} = 25^{\circ}C$			1	μΑ
Gate-Source Leakage	I <sub>GSS</sub>	$V_{GS} = \pm 30V$			±100	nA
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	3.0		4.0	V
Drain-Source On-Resistance (Note3)	R <sub>DS(on)</sub>	$V_{GS} = 10V, I_D = 3.5A$		1.1	1.35	Ω
Dynamic						
Input Capacitance	C <sub>iss</sub>	V 0V		891		pF
Output Capacitance	C <sub>oss</sub>	$V_{GS} = 0V,$ $V_{DS} = 25V,$		87		
Reverse Transfer Capacitance	C <sub>rss</sub>	f = 1.0MHz		10		
Total Gate Charge	$Q_g$			32		nC
Gate-Source Charge	$Q_gs$	$V_{DD} = 520V, I_{D} = 7A,$ $V_{GS} = 10V$		4.6		
Gate-Drain Charge	$Q_{gd}$	165		14		
Turn-on Delay Time	t <sub>d(on)</sub>			39		
Turn-on Rise Time	t <sub>r</sub>	$V_{DD} = 325V, I_{D} = 7A,$		23		
Turn-off Delay Time	t <sub>d(off)</sub>	$R_G = 25 \Omega$		137		ns
Turn-off Fall Time	t <sub>f</sub>			60		
Drain-Source Body Diode Character	istics					
Continuous Body Diode Current	Is	T 25.00			7.0	- A
Pulsed Diode Forward Current	I <sub>SM</sub>	T <sub>C</sub> = 25 °C			28	
Body Diode Voltage	V <sub>SD</sub>	$T_J = 25^{\circ}\text{C}, I_{SD} = 3.5\text{A}, V_{GS} = 0\text{V}$			1.4	V
Reverse Recovery Time	t <sub>rr</sub>	$V_{GS} = 0V, I_{S} = 7A,$		575		ns
Reverse Recovery Charge	Q <sub>rr</sub>	di <sub>F</sub> /dt =100A /μs		1.9		μC

#### **Notes**

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature
- 2. L=10mH,  $V_{DD}$  = 50V,  $R_G$  = 25  $\Omega$ , Starting  $T_J$  = 25  $^{\circ}C$
- 3. Pulse Test: Pulse width ≤ 300µs, Duty Cycle ≤ 1%



#### **Typical Characteristics** $T_J = 25^{\circ}\text{C}$ , unless otherwise noted

Figure 1. Output Characteristics (T<sub>J</sub> = 25°C)

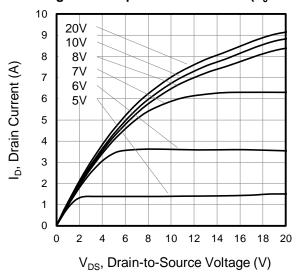


Figure 2. Body Diode Forward Voltage

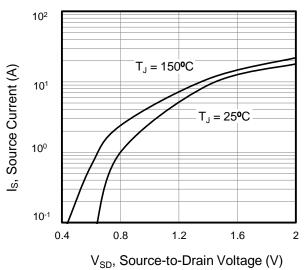


Figure 3. Drain Current vs. Temperature

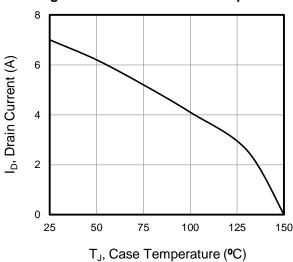


Figure 4. BV<sub>DSS</sub> Variation vs. Temperature

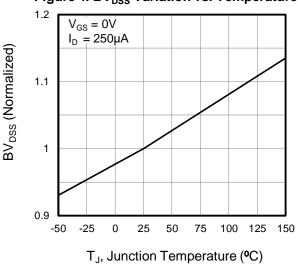


Figure 5. Transfer Characteristics

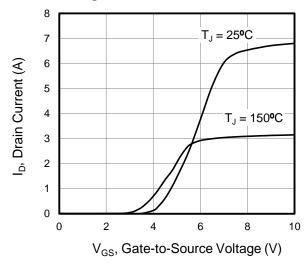
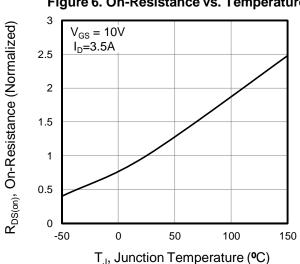


Figure 6. On-Resistance vs. Temperature





### **Typical Characteristics** $T_J = 25^{\circ}\text{C}$ , unless otherwise noted

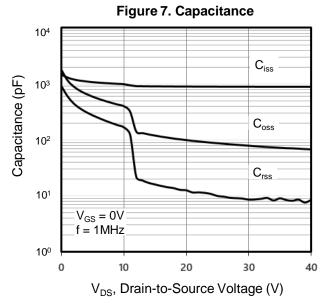


Figure 9. Transient Thermal Impedance
TO-220,TO-251,TO-252

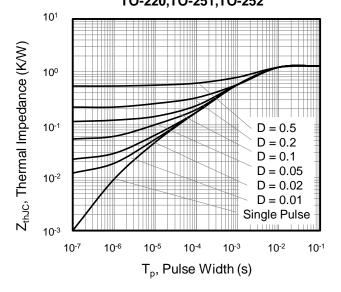


Figure 8. Gate Charge 10 V<sub>GS</sub>, Gate-to-Source Voltage (V)  $V_{DD} = 130V$ 6  $V_{DD} = 325V$  $V_{DD} = 520V$ 2 0 5 10 15 20 25 0 30 35 Q<sub>q</sub>, Total Gate Charge (nC)

Figure 10. Transient Thermal Impedance
TO-220F

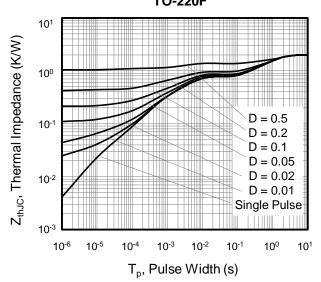




Figure A: Gate Charge Test Circuit and Waveform

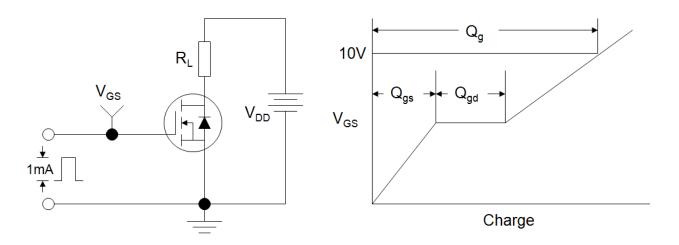


Figure B: Resistive Switching Test Circuit and Waveform

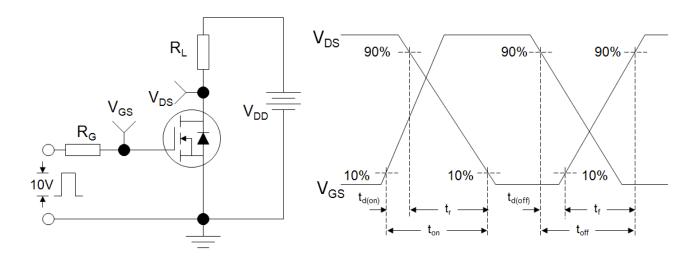
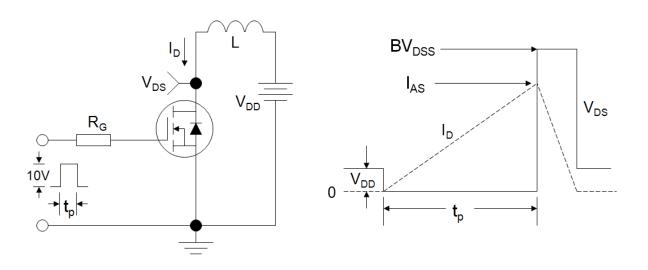
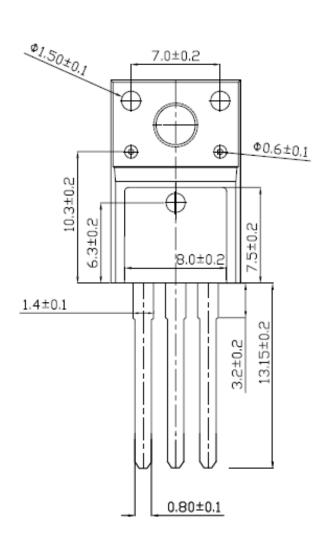


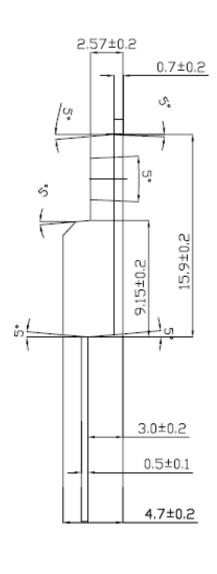
Figure C: Unclamped Inductive Switching Test Circuit and Waveform





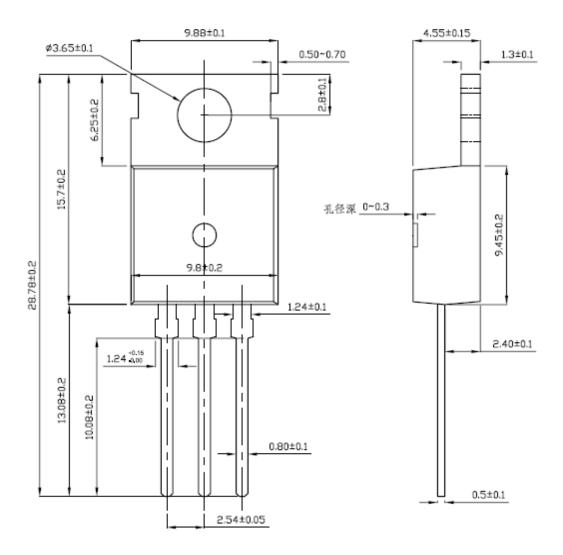
## **TO-220F**





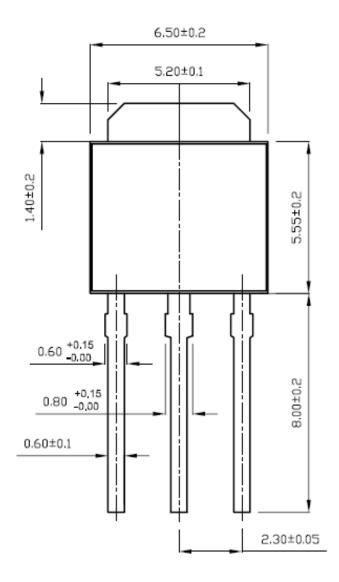


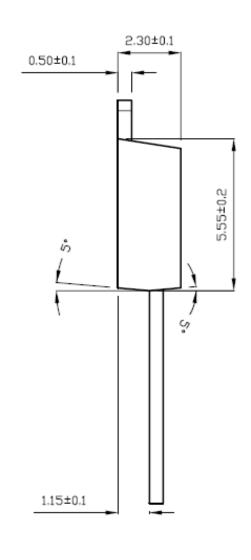
**TO-220** 



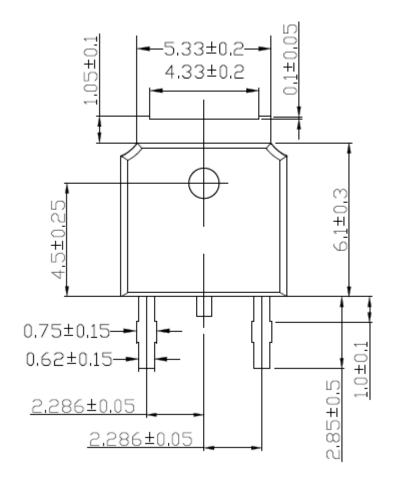


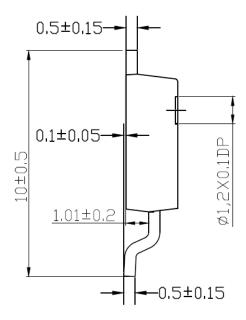
**TO-251** 

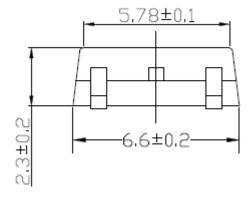




## **TO-252**









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